

| | | | |
|-----------------------------------|---------------------------------------|--|-------------|
| Notice of References Cited | Application/Control No. 10/590,517 | Applicant(s)/Patent Under Reexamination SHIMONO, TAKASHI | |
| | Examiner MONA M. SANEI | Art Unit 2882 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| * | A | US-5,594,768 | 01-1997 | Fujii et al. | 378/21 |
| * | B | US-4,105,922 | 08-1978 | Lambert et al. | 382/131 |
| * | C | US-3,973,127 | 08-1976 | Matsuda et al. | 378/24 |
| * | D | US-5,278,884 | 01-1994 | Eberhard et al. | 378/4 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|-------------|----------------|
| | N | JP2003-024320 | 01-2003 | Japan | Niwa et al. | A61B006/02 |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.